Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination
10/785,402	JUNG, HEE-WON
Examiner	Art Unit

John L. Goodrow

1756

SEARCHED					
Class	Subclass	Date	Examiner		
430	109.2	10/3/2005	JG		
	109.3				
	109.4				
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
inventor name search and east	10/3/2005	JG		
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